

**IEEE MORRIS E. LEEDS AWARD
RECIPIENTS**

Award has been temporarily suspended

2000 - NO AWARD

1999 - NO AWARD

1998 - NO AWARD

1997 - MALVIN C. TEICH
Boston University
Boston, MA, USA
"For outstanding contributions to electrical measurement using infrared and nonlinear heterodyne detection."

1996 - MARK B. KETCHEN
IBM/T.J. Watson Research Center
Yorktown Heights, NY, USA
"For leadership in the development of superconducting devices and technology for instrumentation applications."

1995 - ROGER B. MARKS
DYLAN F. WILLIAMS
NIST
Boulder, CO, USA
"For the development of measurement methods for accurate on-wafer characterization of monolithic microwave integrated circuits."

1994 - OLIVER C. WELLS
IBM/T.J. Watson Research Center
Yorktown Heights, NY, USA
"For contributions to the application of scanning electron microscopy in dimensional, electrical, and magnetic measurements."

1993 - NO AWARD

1992 - H. KUMAR WICKRAMASINGHE
IBM Corporation
Yorktown Heights, NY, USA
"For contributions to electrical techniques for nanometer-scale measurement of magnetic, optical, electrostatic and thermal properties of surfaces."

1991 - DAVID H. AUSTON
Columbia University
New York, NY, USA
"For pioneering work on the generation and detection of ultrashort electrical pulses and their application to studies of optoelectronic materials and devices."

1990 - RYSZARD A. MALEWSKI
Hydro-Quebec Inst. of Re.
Varennes, Quebec, Canada
"For contributions to precision high current and high voltage measurement techniques."

1989 - RAY BARTNIKAS
Inst. de Rech. d'Hydro-Quebec
Varennes, Quebec, Canada
"For the development of widely-used measurement techniques for dielectric materials and insulation systems."

1988 - DAVID V. LANG
AT&T Bell Labs.
Murray Hill, NJ, USA
"For invention of Deep Level Transient Spectroscopy for semiconductor characterization."

1987 - WILLIAM J. M. MOORE
Nat'l Res. Council of Canada
Ottawa, Ontario, Canada
"For contributions to precise current comparators and their application to industrial measurements."

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| 1986 - IAN KAY HARVEY
CSIRO, Nat'l Measurement Lab.
Lindfield, Australia | "For contributions to the use of superconducting phenomena for precision measurements." |
| 1985 - DONALD C. COX
AT&T Bell Labs
Holmdel, NJ, USA | "For outstanding contributions to space-earth millimeter-wave propagation measurements." |
| 1984 - LEONARD SAMUEL CUTLER
Hewlett-Packard Company
Palo Alto, CA, USA | "For outstanding contributions to the development of advanced time standards, in particular to the cesium beam standard." |
| 1983 - ERICH P. IPPEN
M.I.T.
Cambridge, MA, USA
and CHARLES V. SHANK
Bell Labs
Holmdel, NJ, USA | "For their pioneering contributions to extending the techniques of time-domain measurement into the subpicosecond range." |
| 1982 - LOTHAR ROHDE
Rohde & Schwarz
Munich, Germany | "For contributions to the field of precise electronic measurement equipment for very high frequencies." |
| 1981 - FRANK C. CREED
Nat'l Res. Council of Canada
Ottawa, Canada | "For contributions to the theory and practice of high-voltage impulse measurements." |
| 1980 - WALLACE H. COULTER
Coulter Electronics, Inc.
Hialeah, FL, USA | "For his invention and development of basic electrical measurement methods for the counting, sizing and identification of biological cells and inorganic particles." |
| 1979 - ROBERT D. CUTKOSKY
Nat'l Bureau of Standards
Washington, DC, USA | "For internationally significant contributions to the field of precision impedance measurements and standards." |
| 1978 - THOMAS M. DAUPHINEE
Nat'l Res. Council of Canada
Ottawa, Canada | "For the application of physical principles to electrical instrumentation and measurements." |
| 1977 - ARTHUR MELVILLE THOMPSON
Nat'l Measurement Laboratory
Chippendale, Australia | "For outstanding advances in absolute electrical measurements, particularly capacitance and resistance." |
| 1976 - FRANCIS LEWIS HERMACH
Nat'l Bureau of Standards
Washington, DC, USA | "For research and development of extremely accurate ac-dc transfer standards and for outstanding service on standards committees." |
| 1975 - NO AWARD | |

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| 1974 - NORBERT L. KUSTERS
Nat'l Research Council of Canada
Ottawa, Canada | "For inspiring leadership in the field of electrical measurements, in particular for the development of the current comparator and its associated applications." |
| 1973 - CHARLES HOWARD VOLLUM
Tektronix, Inc.
Beaverton, OR, USA | "For outstanding contributions in the field of electrical measurements through many developments of the oscilloscope." |
| 1972 - FOREST K. HARRIS
Nat'l Bureau of Standards
Washington, DC, USA | "For a lifetime of making outstanding advances in the science of high-accuracy electrical measurements, and of stimulating further advances through his teaching, authorship, and committee activity." |
| 1971 - MARTIN E. PACKARD
Varian Associates
Menlo Park, CA, USA | "For his pioneering research leading to the practical use of nuclear magnetic resonance for the accurate measurement of magnetic fields, and for his contributions to the spectrometry of complex molecules." |
| 1970 - HAROLD I. EWEN
Ewen Knight Corp./Ewen Dae Corp.
Natick, MA, USA | "For contributions to the design of sensitive radiometric systems, and for the co-discovery of the 21 cm spectral line of interstellar hydrogen." |
| 1969 - HARRY WILLIAM HOUCK
McGraw
Edison, NJ, USA | "For outstanding contributions to the field of RF instrumentation." |
| 1968 - ALBERT J. WILLIAMS, JR.
Leeds & Northrup Co.
North Wales, PA, USA | "For outstanding contributions to electrical instrumentation and measurement." |
| 1967 - HENRY R. CHOPE
Industrial Nucleonics Corp.
Columbus, OH, USA | "For accomplishment in the field of industrial process measurement through the use of nucleonic and radio-frequency technique." |
| 1966 - WILLIAM W. MUMFORD
AT&T Bell Labs
Whippany, NJ, USA | "For his outstanding contribution to the theory and technique of microwave measurements, including his invention and application of standard noise sources and directional couplers." |
| 1965 - HAROLD E. EDGERTON
M.I.T.
Cambridge, MA, USA | "For his contributions to the field of measurements particularly through the development and application of high speed, high intensity, precisely timed light sources." |
| 1964 - JOHN GILBERT FERGUSON
Lockheed Electronics
Upper Montclair, NJ, USA | "For his contributions in expanding the knowledge of the measurement of fundamental electrical units." |

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| 1963 - FRANCIS B. SILSBEE
Nat'l Bureau of Standards
Washington, DC, USA | "For his contribution to the international standardization of basic electrical units and their measurement." |
| 1962 - BERNARD E. LENEHAN
Westinghouse Electric Corp.
Bloomfield, NJ, USA | "For his keen understanding of electrical measurement phenomena and his outstanding ability to apply fundamental analysis and conceive basically new and sound ideas for solving difficult instrumentation problems." |
| 1961 - THEODORE A. RICH
General Electric Co.
Schenectady, NY, USA | "For outstandingly creative contributions to the field of measurement through exceptional awareness of new measurement needs and timely invention to accomplish the measurement." |
| 1960 - PERRY A. BORDEN
University of Dayton
Dayton, OH, USA | "For outstanding contributions to electrical measurements in the field of recording, control and telemetering; and helpful encouragement to younger colleagues." |
| 1959 - HERBERT B. BROOKS
Nat'l Bureau of Standards
Washington, DC, USA | |